
The influence of Spatial and Transient Circuit Variations on Energy and Accuracy in Stochastic Computing Circuits



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micas



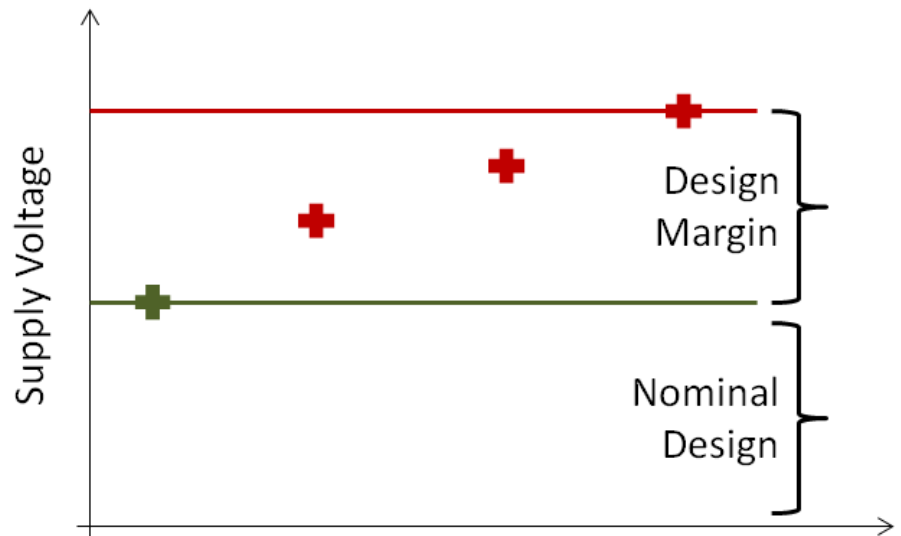
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Presentation outline

- **Introduction**
- Stochastic Computing (SC)
- Noise sources in SC
- Energy dissipation in SC
- Single stage noise analysis
- Conclusion

Introduction

- Advanced technologies are increasingly unreliable.
- In classic digital circuits, faults caused by unreliability are always prevented:
 - Introduction of energy consuming design margins:
 - Higher supply voltage;
 - Longer delays;
 - Conservative Layout;
 - System redundancy.

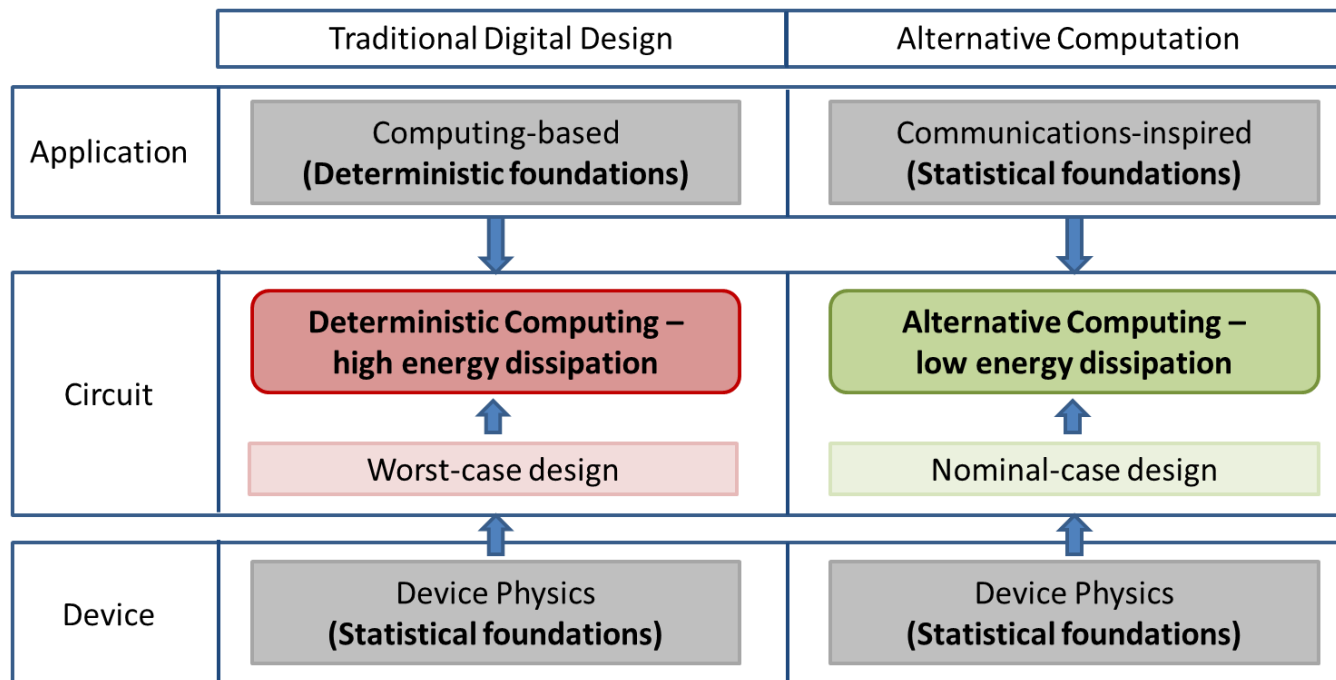


Nominal Design Inter- and intra die variations Supply voltage ringing Radiation effects ...

Introduction

■ Research hypothesis:

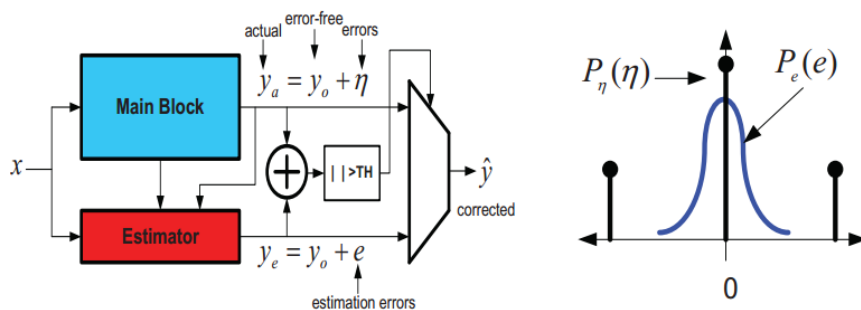
- By allowing controllable faults in digital electronics, the energy consumption in fault tolerant applications can be reduced.
- => No need for energy wasting design margins.



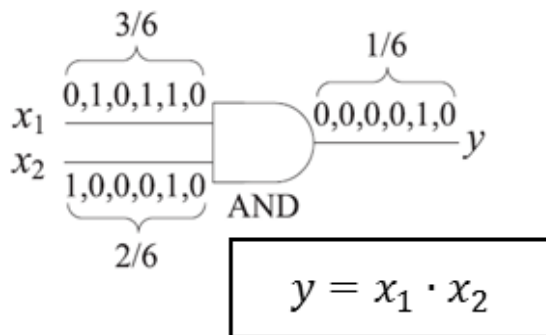
Introduction

■ State-of-the-art Literature

- Imprecise Hardware (pruning of basic binary arithmetic blocks) [1]
- Stochastic Computation: class of techniques exploiting probability theory to deal with uncertainty. (e.g. ANT) [2]



- Stochastic Computing [3]



[1] = Weber, "Balancing adder for error tolerant applications", ISCAS, 2013

[2] = Shanbhag, "stochastic computation", DAC, 2010

[3] = Alaghi, A. , Hayes, J., "Survey of stochastic computing", ACM, 2012

Presentation outline

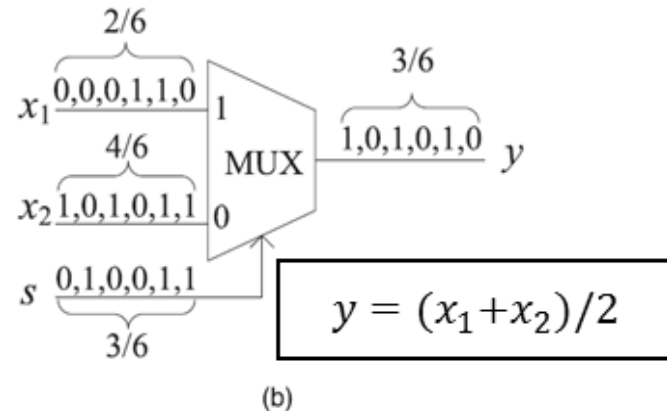
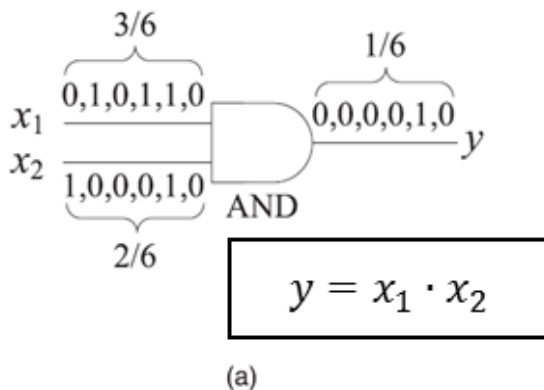
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Stochastic Computing (SC)

- Type of digital logic in which information is represented and processed in the form of digitized probabilities.

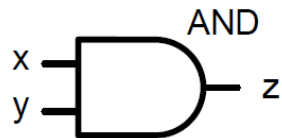
$$\left. \begin{array}{l} 0 \\ 1 \\ 0 \end{array} \right\} = 2 \text{ in 3 bit parallel} \Rightarrow 0,0,1,0,1,0,0,0 \left. \right\} = p = 2/8 \text{ in 8 bit serial}$$

- p equals the probability of any bit of the bit-stream to equal one.
- This leads to simplified hardware:



Stochastic Computing (SC)

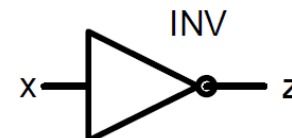
- UP: Unipolar representation - $p \in [0,1]$
- BP: Bipolar representation - $s = 2p - 1 \in [-1,1]$



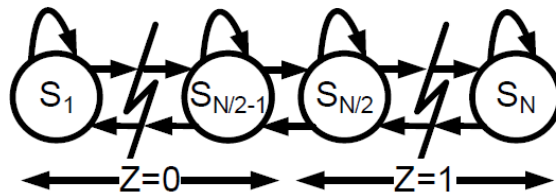
(a) $Z = x \cdot y$ (UP)



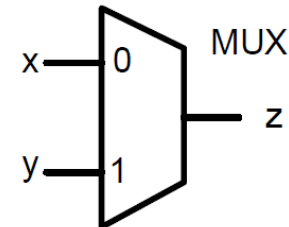
(b) $Z = x \cdot y$ (BP)



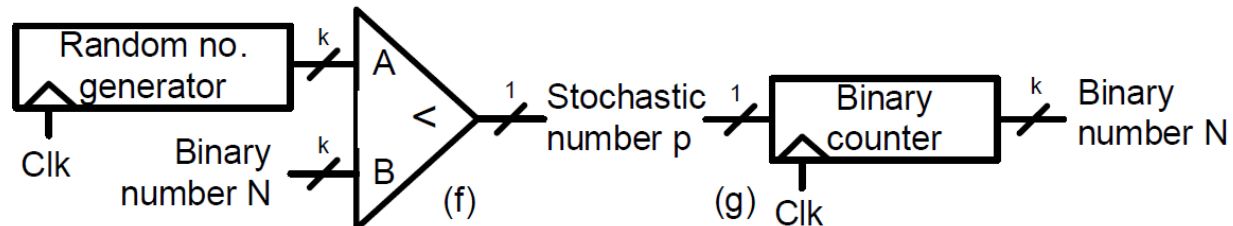
(c) $Z = 1-x$ (UP)
 $= -x$ (BP)



(d) $Z = k \cdot x$ (BP)



(e) $Z = (x+y)/2$ (UP, BP)



Stochastic Computing(SC)

■ Advantages

- Simplified Hardware (highly parallelizable)
- Run-time adaptable precision (easy transition from eg. 8->6 bit precision)
- Inherently fault tolerant (faults on LSB i.s.o. MSB)
 - Binary adder has possible timing errors on MSB
 - Stochastic computation adder only has LSB faults

■ Disadvantages

- Very long bitstreams ($O(2^n)$)

Case study: SC JPEG compression

- Stochastic computing error tolerance example:
 - Stochastic DCT implementation as part of JPEG encoder



CR = 74.5, RMSE = 12.1%

(a) Binary at $p_t = 1e - 3$



CR = 91.2%, RMSE = 2.3%

(b) SC ($L = 2^{16}$) at $p_t = 1e - 3$

Case Study: SC Edge-detection

- Edge-detection performance under different input noise conditions. [4]

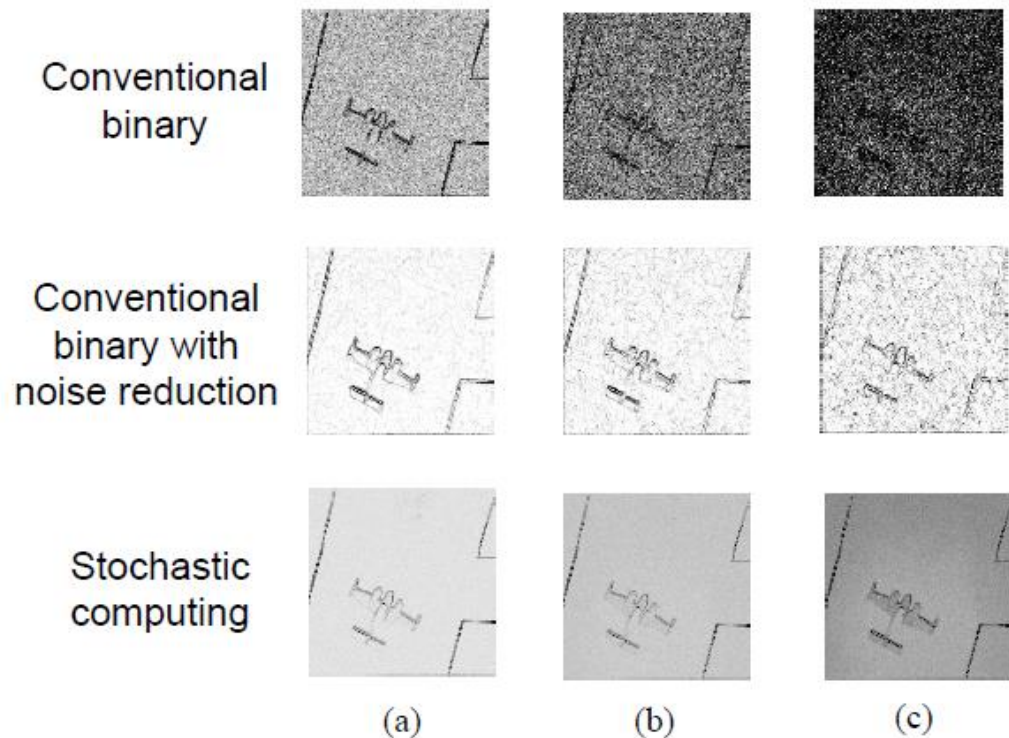


Figure 10. Edge-detection performance for three implementation methods with noise levels of (a) 5%, (b) 10% and (c) 20%.

[4] = Alaghi, A. , Hayes, J.P., "Stochastic Circuits for Real-Time Image-Processing Applications", DAC,2013.

Stochastic Computing

- Paper goal:
 - Quantitatively investigate the performance of Stochastic Computation under the influence of different noise sources / uncertainties.
 - Performance is measured in terms of **energy** and **accuracy**.

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Noise in Stochastic computing

- Errors in digital circuits are mainly due to:

Type I: Inherent inaccuracy	Random in time and space Binary: quantization noise SC: noise due to randomness
Type II: Spatial circuit variations	Fixed in time and space All types of inter- and intra-die variations
Type III: Transient circuit variations	Random in time and space <ul style="list-style-type: none">- Random bit-flips;- Supply voltage ringing;- Radiation effects.

Type I: inherent inaccuracy

- Inherent noise in stochastic Computing is binomial:

$$\sigma_{mean SC}^2 = RMSE^2 = \int_0^1 \frac{p(1-p)}{L} dp = \frac{1}{6L}$$

- Binary quantization noise:

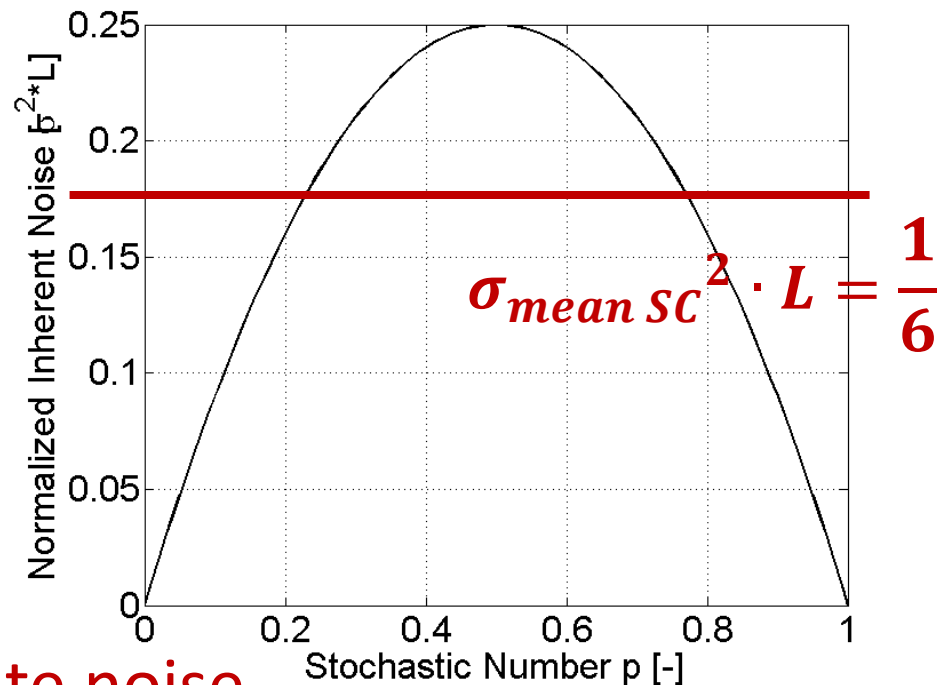
$$\sigma_{bin}^2 = \frac{\delta^2}{12} = \frac{1}{12 \cdot 2^{2n}}$$

- Comparison:

$$\sigma_{SC}^2 = \sigma_{bin}^2 \Leftrightarrow L = 2^{2n+1}$$

$\Rightarrow n=4 \Rightarrow L=512$ at equal

mean absolute noise



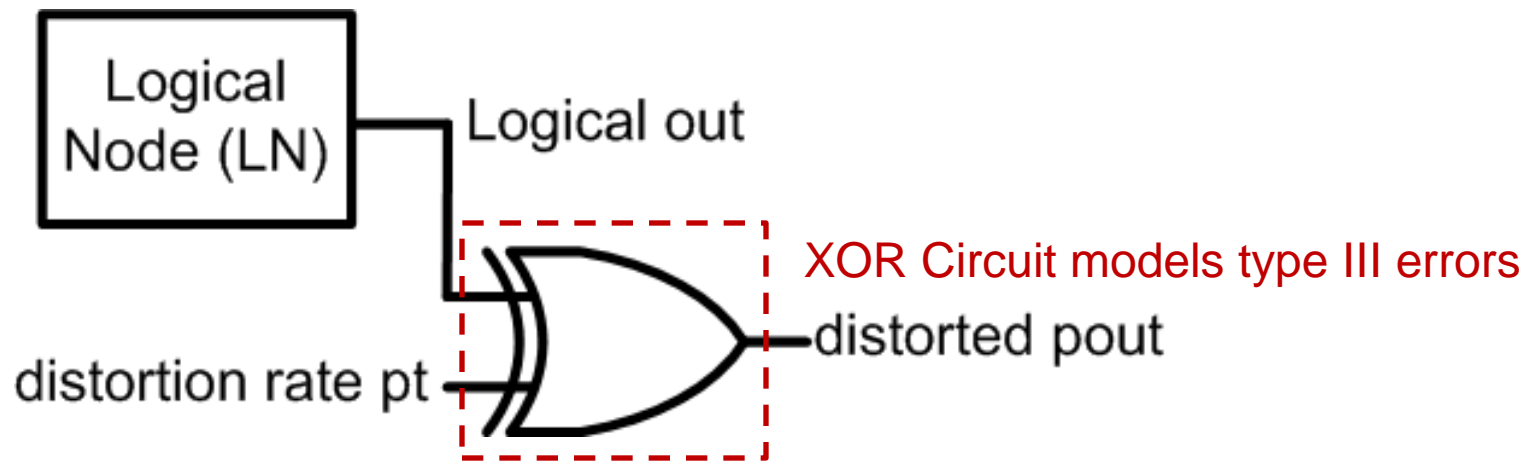
Type II: spatial inaccuracy

- **Dominant** circuit uncertainty
- Should be **tuned out**
 - Random spatial variations are fixed in time and space after production.
 - Faults due to spatial variations become repetitive and deterministic!

Type III: transient inaccuracy

- Can be modelled by extending the stochastic circuitry with XOR-gates at its outputs.

$$p_{out_{distorted}} = xor(p_{out}, distortion\ rate\ p_t)$$



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Energy dissipation in SC

- Energy scales linearly with bit-stream length L
 - k = Energy/bit-operation = function of V and f
 - L = bit-stream length

$$E_{SC} = k \cdot L$$

- Energy in a system suffering from type I errors.

$$E_{SC} = \frac{k}{6 \cdot RMSE^2}$$

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Simulation Set-up

- Tested circuits:
 - Stochastic: Unipolar AND-gate multiplier;
 - Binary: Standard RC-multiplier.
- Comparison is for same overall delay (32ns).
- Supply voltage is swept at given clock freq.
- Minimal supply voltage at which no type II errors occur is used to assess the impact of type I and III errors => **simulated energy/word is the minimal energy.**

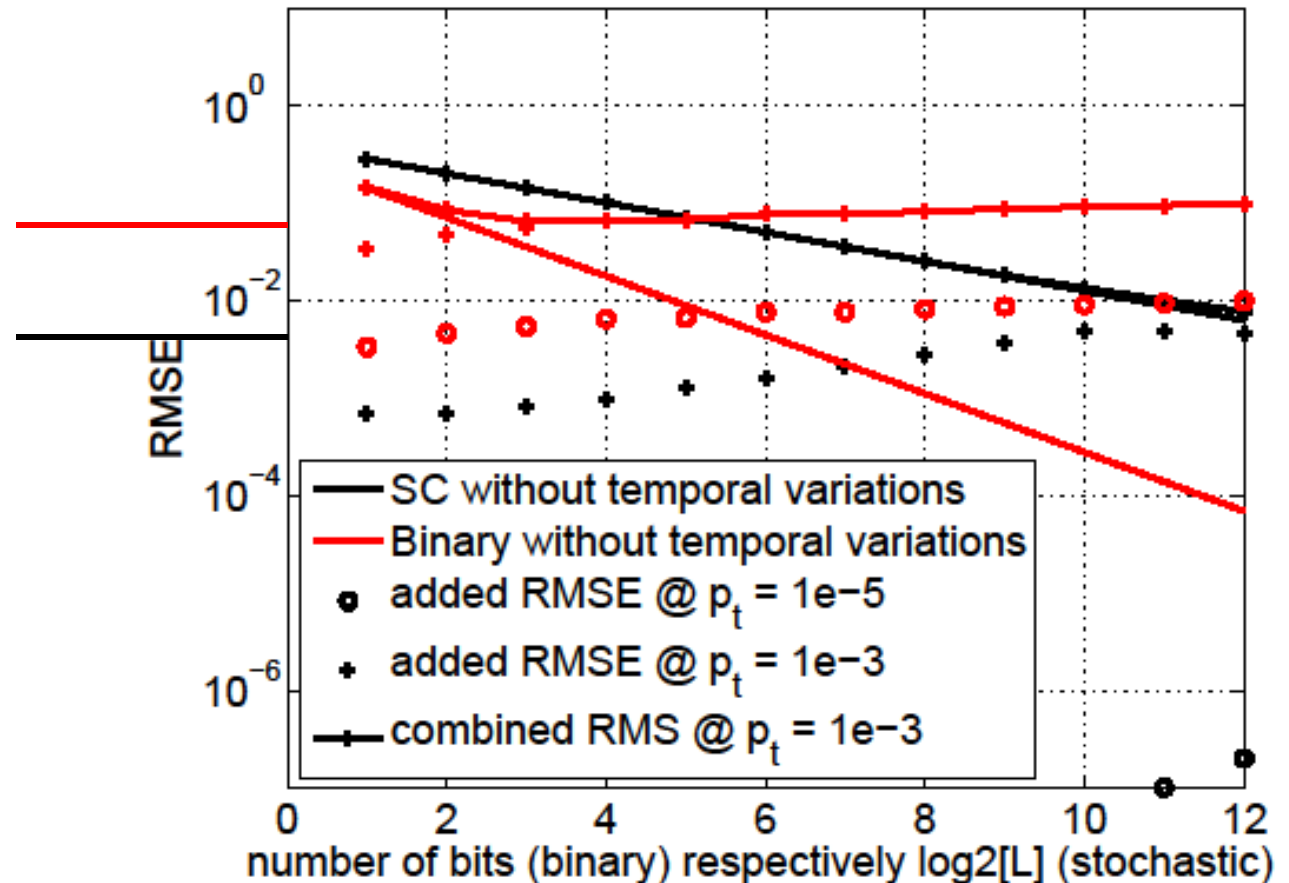
Single stage noise analysis: type I + type III

p_t = transient error rate

Binary lower limit
@ $p_t = 1e-3$

SC lower limit
@ $p_t = 1e-3$

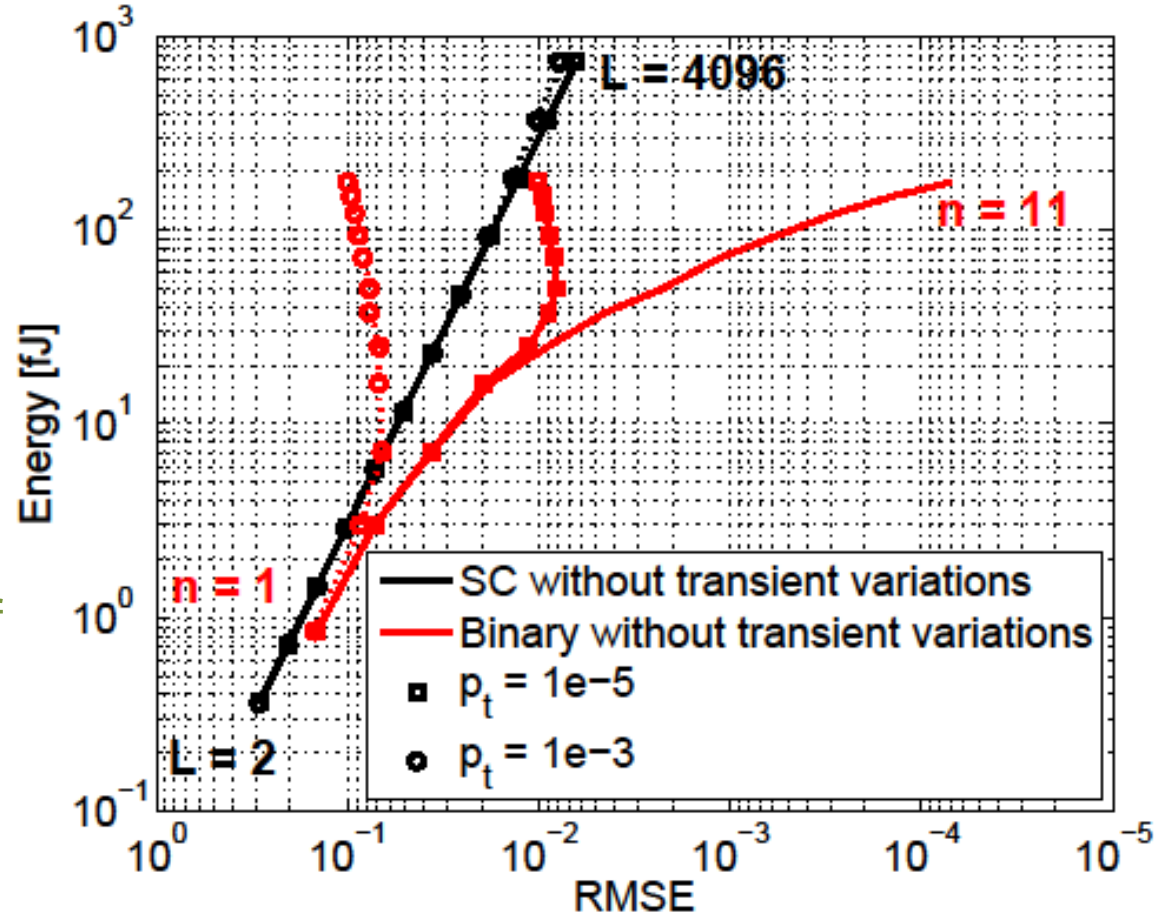
RMSE versus binary precision (n) and
stochastic length (L)



Single stage noise analysis: type I + type III

- Binary
 - Invest more energy:
⇒ RMSE does not drop
- SC
 - Invest more energy:
⇒ RMSE drops
- ⇒ SC allows to trade-off energy for precision, even when transient errors are present

Energy versus RMSE in circuits suffering from transient variations



Single stage noise analysis: type I + type II

Energy versus RMSE in circuits suffering from spatial variations

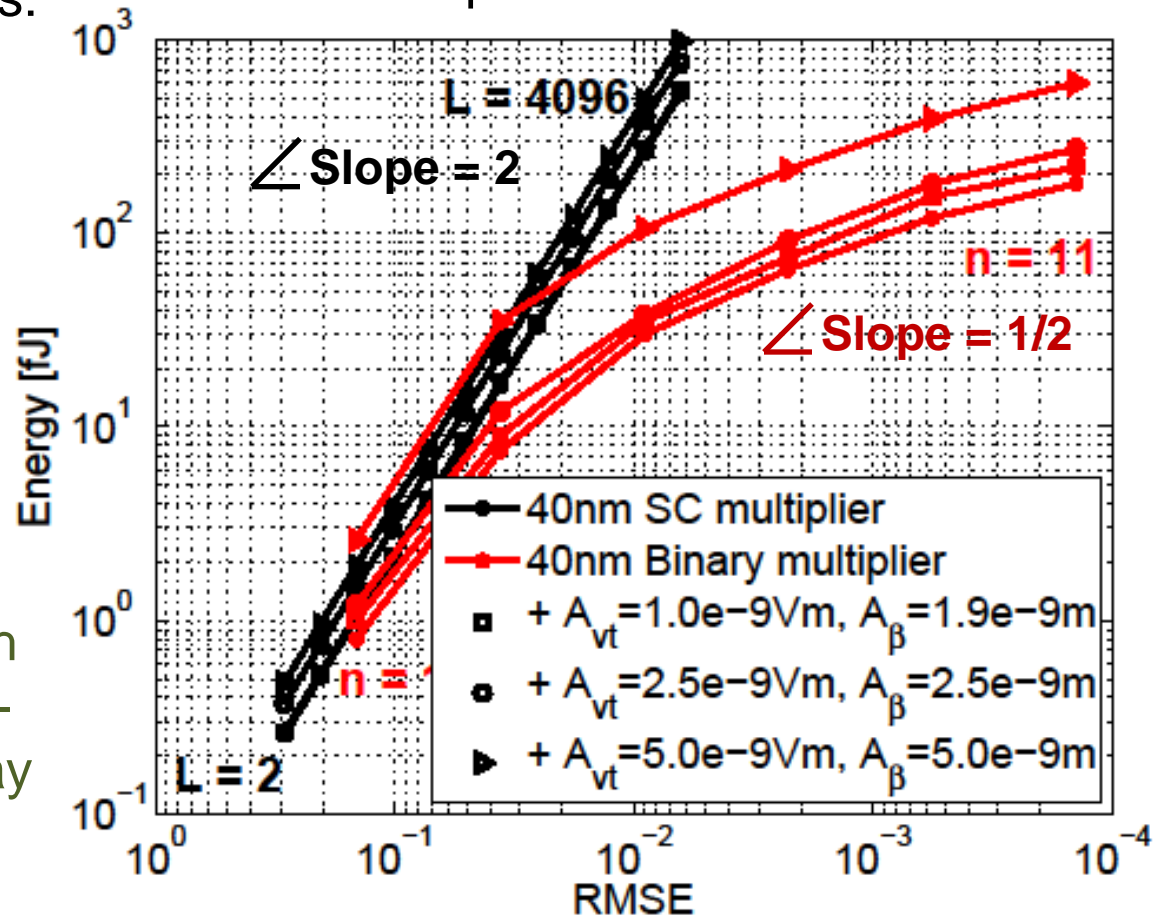
- Higher spatial variations:

- ⇒ More energy needed to reach given RMSE.

$$E_{SC} = \frac{k}{6 \cdot RMSE^2 \cdot C}$$

$$E_{bin} = \frac{1}{RMSE^2}$$

- In technologies with very low energy/bit-operation k , SC may outperform binary.



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Conclusion

- **Inherent noise** in SC is much larger than in Binary.
- SC greatly outperforms binary logic when transient variations are present. Under these circumstances **it can still trade-off energy for precision by using longer bit-streams**, while binary logic can not.
- SC may be a good alternative to binary in technologies with a **low k (energy per bit-operation)** that suffer from significant transient circuit variations.

Thank you!

QUESTIONS?

